

HyFBIST : hybrid functional built-in self-test in microprogrammed data-paths of digital systems

Ubar, Raimund-Johannes; Mazurova, Natalja; Smahtina, Julia; **Orasson, Elmet**; **Raik, Jaan** Proceedings of the 11th International Conference : Mixed Design of Integrated Circuits and Systems : MIXDES 2004 : Szczecin, Poland, 24-26 June 2004 2004 / p. 497-502 : ill

Sequential circuits BIST with status bit control

Raik, Jaan; **Orasson, Elmet**; **Ubar, Raimund-Johannes** Proceedings of the 11th International Conference : Mixed Design of Integrated Circuits and Systems : MIXDES 2004 : Szczecin, Poland, 24-26 June 2004 2004 / p. 507-510 : ill
https://pld.ttu.ee/~raiub/files/aaaaa_pulk/MIXDES/jaan.pdf